

BACK-END

DIODE

SCR

TRIAC

IFSM TESTER IFSMテスター

IFSM40ZZRP 4000A

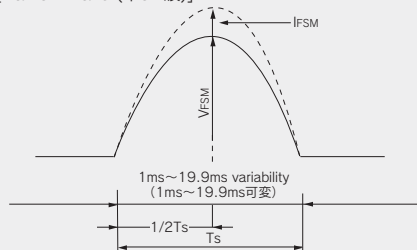
NEW



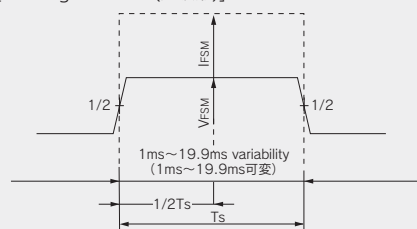
- IFSM40ZZRP is designed to guarantee tolerance of IFSM which is non-repetitive maximum current of diode by forcing and measuring peak voltage value at the forcing. This system is able to carry out constant measurement 2 elements at maximum.
- IFSM40ZZRPはダイオードの非繰り返し最大電流であるIFSMを印加し、その時のピーク電圧値を測定することで、IFSMの耐量を保証するシステムです。2素子までの連続測定が可能です。

### Measurement Waveform

[Half sin wave (半正弦波)]

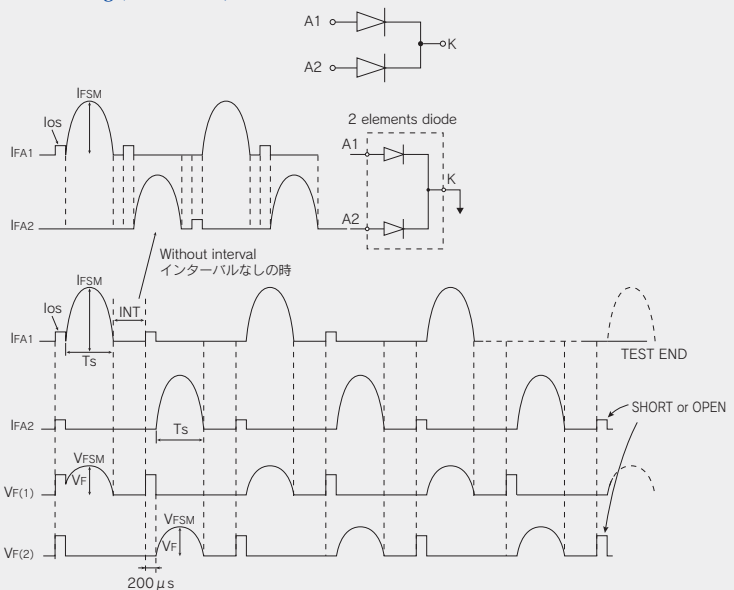


[Rectangular wave (短波形)]



The time of rise up and down are less than  $500 \mu\text{s}$  at 4000A.  
4000Aの立上がり、立下がり時間は $500 \mu\text{s}$ 以下とする。

### Test Timing (2 Elements)



MODEL	IFSM40ZZRP	
MEASUREMENT RANGE		
IP	0000A~4095A	
VFSM	0.00V~19.99V	
IFSM SETTING		
MODE	SIN/SQUARE	
IOS	10mA~999mA (Fixed $200 \mu\text{s}$ )	
IFSM	1A~4000A	
IGK1/IGK2	1mA~500mA	
Ts	1.0ms~19.9ms	
INTERVAL TIME	0.0ms~99.9ms	
CYCLE	1~9999	
OPEN GATE/SHORT GATE	0.000V~9.999V	
VFSM LOW GATE/HIGH GATE	0.00V~19.99V	
IR SETTING		
VR	0.01kV~1.99kV	
Tw	2ms~999ms	
IR	0.000mA~9.999mA	
BINNING		
OPEN/SHORT CHECK	OPEN...Vos > 0.000V~9.999V 0.001V STEP SHORT...Vos < 0.000V~9.999V 0.001V STEP	
BIN INDICATION	PRE SHORT, PRE OPEN, VFSM LOW, VFSM HIGH, POST SHORT, POST OPEN, PASS	
DIMENSIONS & WEIGHT		
MAIN UNIT	1650(W)×1060+600(D)×1770(H)…1760kg	